Have Faith in Faithfulness: Going Beyond Circuit Overlap When Finding Model Mechanisms

Michael Hanna, Sandro Pezzelle, Yonatan Belinkov m.w.hanna@uva.nl, s.pezzelle@uva.nl, belinkov@technion.ac.il





Localizing Task Performance in LMs

To localize a task, we find a **circuit**: the minimal computational subgraph that preserves LM behavior when corrupting all other edges.



Tasks

Indirect Object Identification (IOI, 7): When John and Mary went to the store, <John/Alice> gave a drink to [Mary/John] Greater-Than [8]: The war lasted from the year <1741/1701> to the year 17[02/42]

- **Price:** The price ranges from \$...
- Sequence: 1663,1687,1694,<1741/1701>,17

Gendered Pronouns: The <nurse/doctor> said that [she/he] SVA [9]: The <keys/key> on the cabinet [are/is]

Capital-Country: <France/Italy>, whose capital, [Paris/Rome]

• **Country-Capital**: [Paris/Rome], the capital of [France/Italy] **Hypernymy:** <Roses/diamonds> and other [flowers/gems]

Prior Circuit Finding Methods

Past approaches found a singular circuit using patching. Newer approaches score edge importance, then find a circuit using those scores; you can choose the circuit size. But how to get scores?

- Activation Patching [1] patches an edge's corrupted activation into a clean forward pass. This requires *O(edges)* passes.
- EAP [2]: approximates the impact of ablating an edge (u,v) as $(z'_u - z_u)^\top \nabla_v L(s),$ where z_u/z_u' are u's clean / corrupted acts; L(s) is the loss when

running the model on a clean example. This requires O(1) passes.

Integrated-Gradients-Based Methods



Integrated gradients [3] is a technique like EAP that attempts to find important parts of the inputs. It improves inputs *x* gradients by interpolating between inputs when computing gradients.

Comparing Methods

We find circuits of varying sizes for these tasks in GPT-2 small. EAP-IG (in input or activation space) outperforms EAP. The Clean-Corrupted method is a strong baseline, often as good as EAP-IG.



Inter-Task Comparison

We measure **intersection over union** (# overlapping nodes ÷ total # nodes) & **cross-task faithfulness** (run one task on another's circuit)

	Node Interportion over Union	Edge Interposition over Union	Cross Task Faithfulsess
	Node Intersection over Onion	Edge Intersection over Onion	Cross-Task Faithumess
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$$(z_t - z'_t) \int_{\alpha=0}^1 \frac{\partial M(z' + \alpha(z - z'))}{\partial z_t} \approx (z_t - z'_t) \frac{1}{m} \sum_{k=1}^m \frac{\partial M(z' + \frac{k}{m}(z - z'))}{\partial z_t},$$

How can we use this technique for circuit finding?

- EAP-IG (Inputs, ours): Average grads over input interpolation; *O*(*m*)
- EAP-IG (Activations) [4]: Average grads over interpolation between activations—in O(m*layers) passes.
- EAP-IG (Activations) [5]: Try to do the former in *O*(*m*) passes.
- Clean-Corrupted: Average grads on clean / corrupted inputs; O(1)

$$(z'_u - z_u)\frac{1}{m}\sum_{k=1}^{n}\frac{\partial L(z + \frac{m}{m}(z - z))}{\partial z_v}$$

1 $m \partial I(z' \pm \frac{k}{2}(z - z'))$

 $(z'_u - z_u)\frac{1}{m}\sum_{k=1}^m \frac{\partial L(s|\operatorname{do}(z_u = z'_u + \frac{k}{m}(z_u - z'_u))}{\partial z_v}$

$$(z'_u - z_u)\frac{1}{m}\sum_{k=1}^m \frac{\partial L(s|\operatorname{do}(\forall n \in V : z_n = z'_n + \frac{k}{m}(z_n - z'_n))}{\partial z_v}$$

$$(z'_u - z_u)^{\top} \left(\frac{1}{2}\nabla_v L(s) + \frac{1}{2}\nabla_v L(s')\right)$$



Conclusions and Open Questions

- Alternative patching methods, like EAP-IG and Clean-Corrupted, outperform vanilla EAP at little to no extra cost
- Overlap and cross-task faithfulness disagree on circuit similarity
 Still, questions remain:
- Which metric, if any, best quantifies how similar circuits are?
- Can we judge mechanistic similarity via component circuits alone?
- Are these techniques yielding complete circuits?

